Session 1B: Mixed-Signal DFT
Moderators:
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A. Osseiram, EPFL, Switzerland

Defect-oriented DFT methodology. DFT structure. On-Line DFT from IC’s to Boards.

Defect Oriented Test Methodology for Complex Mixed-Signal Circuits
F.C.M. Kuijstermans, A.P. Thijssen, and M. Sachdev

A Design-for-Test Structure for Optimising Analogue and Mixed Signal IC Test
A.H. Bratt, A.M.D. Richardson, R.J. Harvey, and A.P. Dorey

Mixed-Signal Circuits and Boards for High Safety Applications
M. Lubaszewski, V. Kolarik, S. Mir, C. Nielen, and B. Courtois